

## FNK N-Channel Enhancement Mode Power MOSFET

## **Description**

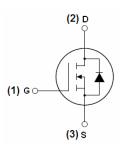
The FNK01N15 uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

#### **General Features**

- $V_{DS} = 100V, I_D = 150A$  $R_{DS(ON)} < 5.7mΩ @ V_{GS} = 10V$  (Typ:5.0mΩ)
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E<sub>AS</sub>
- Excellent package for good heat dissipation

# **Application**

- Power switching application
- Load switching
- Uninterruptible power supply



Schematic diagram



To-220 Top View

## **Package Marking and Ordering Information**

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
FNK01N15	FNK01N15	TO-220	-	-	-

### Absolute Maximum Ratings (T<sub>C</sub>=25 ℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V <sub>DS</sub>	100	V
Gate-Source Voltage	Vgs	±20	V
Drain Current-Continuous	I <sub>D</sub>	150	А
Drain Current-Continuous(T <sub>C</sub> =100 °C)	I <sub>D</sub> (100℃)	113	А
Pulsed Drain Current	I <sub>DM</sub>	580	А
Maximum Power Dissipation	P <sub>D</sub>	370	W
Derating factor		2.5	W/℃
Single pulse avalanche energy (Note 5)	E <sub>AS</sub>	433	mJ

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# FNK01N15

Parameter	Symbol	Limit	Unit
Operating Junction and Storage Temperature Range	$T_J, T_STG$	-55 To 175	$^{\circ}$ C
Thermal Characteristic			
Thermal Resistance,Junction-to-Case <sup>(Note 2)</sup>	R <sub>eJC</sub>	0.4	°C/W

# Electrical Characteristics (T<sub>C</sub>=25 °C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics			•			
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =250μA	100	110	-	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =100V,V <sub>GS</sub> =0V	-	-	1	μΑ
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V,V <sub>DS</sub> =0V	-	-	±100	nA
On Characteristics (Note 3)						
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS}=V_{GS}$ , $I_{D}=250\mu A$	2	2.8	4	V
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =20A	-	5.0	5.7	mΩ
Forward Transconductance	<b>g</b> FS	V <sub>DS</sub> =5V,I <sub>D</sub> =20A	70	-	-	S
Dynamic Characteristics (Note4)						
Input Capacitance	C <sub>lss</sub>	\/ -25\/\/ -0\/	-	6470	-	PF
Output Capacitance	Coss	$V_{DS}$ =25V, $V_{GS}$ =0V, F=1.0MHz	-	690	-	PF
Reverse Transfer Capacitance	C <sub>rss</sub>	r=1.0lvln2	-	430	-	PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	t <sub>d(on)</sub>		-	28	-	nS
Turn-on Rise Time	t <sub>r</sub>	$V_{DD}$ =50V, $R_L$ =2.5 $\Omega$	-	22	-	nS
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GS}$ =10 $V$ , $R_{GEN}$ =3 $\Omega$	-	43.5	-	nS
Turn-Off Fall Time	t <sub>f</sub>		-	14.5	-	nS
Total Gate Charge	Qg	\/ -E0\/1 -20A	-	139	-	nC
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS}$ =50V, $I_{D}$ =20A, $V_{GS}$ =10V	-	34	-	nC
Gate-Drain Charge	$Q_{gd}$	VGS-10V	-	56	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage (Note 3)	V <sub>SD</sub>	V <sub>GS</sub> =0V,I <sub>S</sub> =20A	-	0.85	1.2	V
Diode Forward Current (Note 2)	Is		-	-	160	Α
Reverse Recovery Time	t <sub>rr</sub>	TJ = 25°C, IF =20A	-	60	90	nS
Reverse Recovery Charge	Qrr	$di/dt = 100A/\mu s^{(Note3)}$	-	177	200	nC

#### Notes:

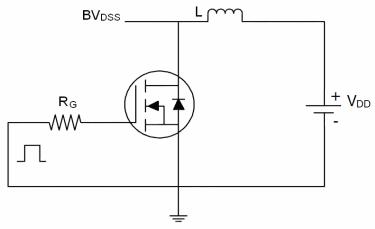
- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- 3. Pulse Test: Pulse Width  $\leq$  300 $\mu$ s, Duty Cycle  $\leq$  2%.
- 4. Guaranteed by design, not subject to production
- 5. EAS condition:Tj=25  $^{\circ}\text{C}$  ,V\_DD=50V,V\_G=10V,L=0.5mH,Rg=25 $\Omega$

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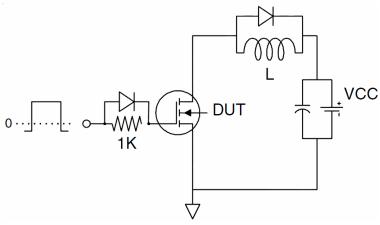


## **Test Circuit**

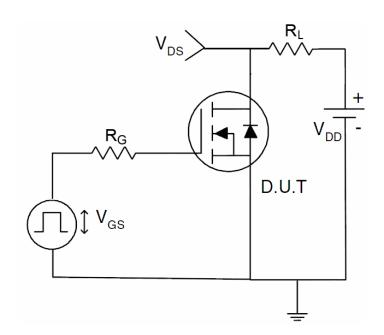
# 1) E<sub>AS</sub> test Circuit



# 2) Gate charge test Circuit



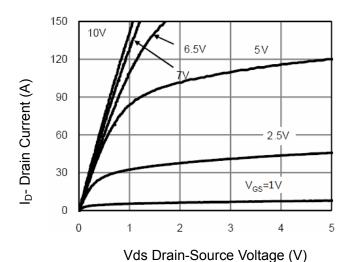
## 3) Switch Time Test Circuit



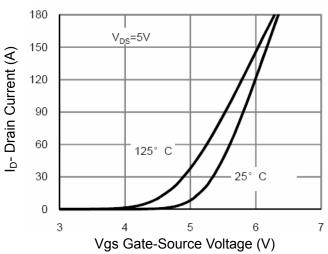
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## **Typical Electrical and Thermal Characteristics (Curves)**



**Figure 1 Output Characteristics** 



**Figure 2 Transfer Characteristics** 

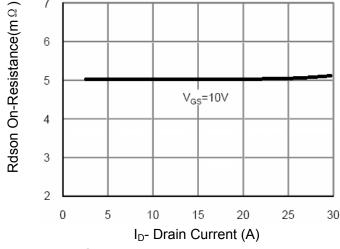


Figure 3 Rdson- Drain Current

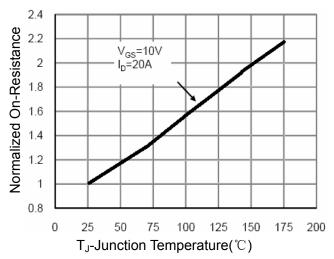


Figure 4 Rdson-JunctionTemperature

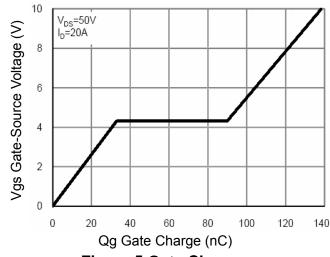


Figure 5 Gate Charge

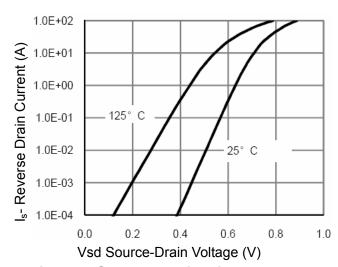
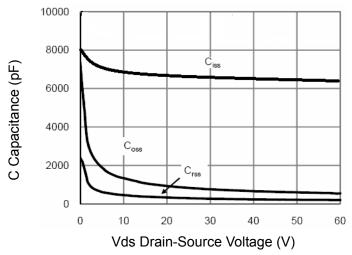


Figure 6 Source- Drain Diode Forward





Ip- Drain Current (A) 40 0

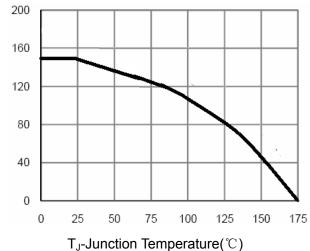


Figure 7 Capacitance vs Vds

**Figure 9 ID Current- Junction Temperature** 

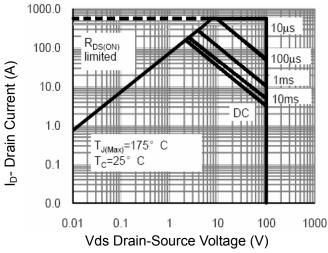


Figure 8 Safe Operation Area

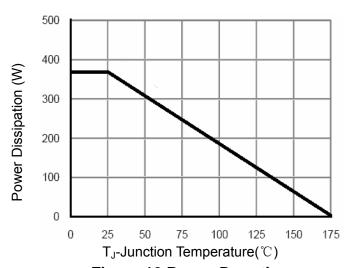


Figure 10 Power De-rating

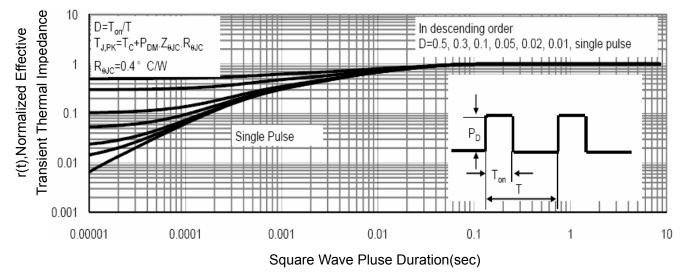
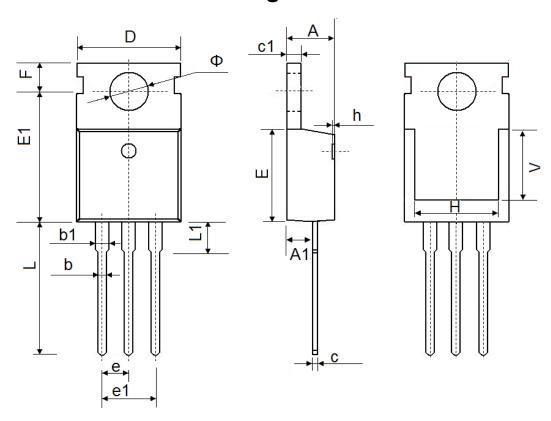


Figure 11 Normalized Maximum Transient Thermal Impedance

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# **TO-220 Package Information**



Symbol	Dimen	sions In Millimeters	Dimensions In Inches		
	Min.	Max.	Min.	Max	
А	4.400	4.600	0.173	0.181	
A1	2.250	2.550	0.089	0.100	
b	0.710	0.910	0.028	0.036	
b1	1.170	1.370	0.046	0.054	
С	0.330	0.650	0.013	0.026	
c1	1.200	1.400	0.047	0.055	
D	9.910	10.250	0.390	0.404	
E	8.9500	9.750	0.352	0.384	
E1	12.650	12.950	0.498	0.510	
е	2.540	TYP.	0.100TYP.		
e1	4.980	5.180	0.196	0.204	
F	2.650	2.950	0.104	0.116	
Н	7.900	8.100	0.311	0.319	
h	0.000	0.300	0.000	0.012	
L	12.900	13.400	0.508	0.528	
L1	2.850	3.250	0.112	0.128	
V	7.500 REF.		0.295 REF.		
Ф	3.400	3.800	0.134	0.150	

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